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Measurement of negative ion mobility varying with a little amount of H_2O in O_2 YUI OKUYAMA, SUSUMU SUZUKI, HARUO ITOH, Chiba Institute of Technology — A study of transport properties such as a mobility of charged particles is importance in understanding discharge plasmas. These fundamental data have been collected in some databases. The authors have been investigated the effects of impurities such as H₂O, CO₂, N₂ on the negative ion mobility in O_2 at high pressures including atmospheric pressure [1, 2]. Especially, the effect of a trace amount of H_2O in O_2 could not to be avoided for the mobility measurement due to formation of cluster ions $O_2^- \cdot (H_2O)_n$ (n = 1, 2, 3, ...). In this study, the mobility of negative ions was measured in O_2 varying with the H_2O concentration from 100 to 17000 ppb. The H_2O concentration was monitored with a trace moisture analyzer whose operation was based on a photoabsorption method. As the results, a constant mobility of 2.39 cm²/V·s was observed in ultrahigh-purity O_2 (99.99995%, purified with a gas purifier), in which the H_2O concentration was monitored to be between 15 and 100 ppb. This value was good agreement with the mobility of O_4^- in previous report [1]. Then, a small amount of H_2O from 2000 to 17000 ppb was added to the ultrahigh-purity O_2 . Two kinds of mobilities 2.31 and $2.21 \text{ cm}^2/\text{V}$ were observed in H₂O concentration ranges of 2000 - 4600 and 4600 -17000 ppb, respectively. Former one is good agreement with the mobility observed in high-purity O_2 (99.9999%) [2]. These mobilities are considered to be those of $O_2^- \cdot (H_2O)_n$ (n = 1, 2). [1] Y. Okuyama et al, 66th Annual Gaseous Electronic Conference, 57, 8, MR1.00091 (2013). [2] Y. Okuyama et al, J. Phys. D: Appl. Phys., 45, 195202 (2012).

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